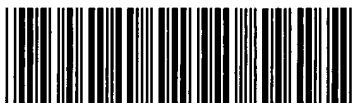


Search Notes

Application/Control No.

10/648,340

Examiner

Wen-Ying P. Chen

Applicant(s)/Patent under
Reexamination

OGISHIMA ET AL.

Art Unit

2871

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
349/110-111 combined with key words search of all databases in EAST	2/28/2006	WPC
349/129 combined with key words search of all databases in EAST	2/28/2006	WPC
Reviewed previously cited references	3/6/2006	WPC